

Effective on 12/08/2004.
Fees pursuant to the Consolidated Appropriations Act, 2005 (H.R. 4818).

FEE TRANSMITTAL

For FY 2005

☒ Applicant claims small entity status. See 37 CFR 1.27

TOTAL AMOUNT OF PAYMENT (\$) 555.00

Complete if Known

Application Number	10/684,120
Filing Date	10/10/2003
First Named Inventor	Christof Baur et al.
Examiner Name	Berman, Jack I.
Art Unit	2881
Attorney Docket No.	34003.55

METHOD OF PAYMENT (check all that apply)

☒ Check ☐ Credit Card ☐ Money Order ☐ None ☐ Other (please identify): _____

☒ Deposit Account Deposit Account Number: 08-1394 Deposit Account Name: Haynes and Boone, LLP

For the above-identified deposit account, the Director is hereby authorized to: (check all that apply)

☐ Charge fee(s) indicated below ☐ Charge fee(s) indicated below, except for the filing fee

☒ Charge any additional fee(s) or underpayments of fee(s) under 37 CFR 1.16 and 1.17 ☒ Credit any overpayments

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FEE CALCULATION

1. BASIC FILING, SEARCH, AND EXAMINATION FEES

Application Type	FILING FEES		SEARCH FEES		EXAMINATION FEES		Fees Paid (\$)
	Fee (\$)	Small Entity Fee (\$)	Fee (\$)	Small Entity Fee (\$)	Fee (\$)	Small Entity Fee (\$)	
Utility	300	150	500	250	200	100	
Design	200	100	100	50	130	65	
Plant	200	100	300	150	160	80	
Reissue	300	150	500	250	600	300	
Provisional	200	100	0	0	0	0	

2. EXCESS CLAIM FEES

Fee Description	Fee (\$)	Small Entity Fee (\$)
Each claim over 20 or, for Reissues, each claim over 20 and more than in the original patent	50	25
Each independent claim over 3 or, for Reissues, each independent claim more than in the original patent	200	100
Multiple dependent claims	360	180

Total Claims Extra Claims Fee (\$) Fee Paid (\$)
48 - 37 - 20 or HP = 11 x 25 = 275

HP = highest number of total claims paid for, if greater than 20

Indep. Claims Extra Claims Fee (\$) Fee Paid (\$)
5 - 4 - 3 or HP = 1 x 100 = 100

HP = highest number of independent claims paid for, if greater than 3

Multiple Dependent Claims
Fee (\$) Fee Paid (\$)

3. APPLICATION SIZE FEE

If the specification and drawings exceed 100 sheets of paper, the application size fee due is \$250 (\$125 for small entity) for each additional 50 sheets or fraction thereof. See 35 U.S.C. 41(a)(1)(G) and 37 CFR 1.16(s).

Total Sheets Extra Sheets Number of each additional 50 or fraction thereof Fee (\$) Fee Paid (\$)
_____ - 100 = _____ / 50 = _____ (round up to a whole number) x _____ = _____

4. OTHER FEE(S)

Non-English Specification, \$130 fee (no small entity discount)

Other: Information Disclosure Statement

Fees Paid (\$)

\$180.00

SUBMITTED BY


Signature		Registration No. (Attorney/Agent) 42,531	Telephone 214-651-5662
Name (Print/Type)	Priscilla L. Ferguson	Date January 25, 2005	

This collection of information is required by 37 CFR 1.136. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 30 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Respectfully submitted,


Priscilla L. Ferguson
Registration No. 42,531

Date: January 25, 2005

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D-1311545.1

EXPRESS MAIL NO.: EV369674305 US

DATE OF DEPOSIT: 1/25/2005

This paper and fee are being deposited with the U.S. Postal Service Express Mail Post Office to Addressee service under 37 CFR §1.10 on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Ellen Lovelace

Name of person mailing paper and fee

Ellen Lovelace

Signature of person mailing paper and fee

In place of PTO-1449 Form		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/684,120
				Filing Date	October 10, 2003
				Applicant(s)	Christof Baur, et al.
				Art Unit	2881
				Examiner Name	Jack I. Berman
SHEET	1	OF	2	Attorney Docket Number	34003.55

U.S. PATENT DOCUMENTS				
Examiner's Initials	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
	A1	5,144,148	09/01/1992	Donald M. Eigler

OTHER PRIOR ART		
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume-issue number(s), publisher, city/country where published
	A2	M.T. CUBERES, R.R. SCHLITTLER, J.K. GIMZEWSKI; <i>Manipulation of C₆₀ molecules on Cu(111) surfaces using a scanning tunneling microscope</i> ; Appl. Phys. A 66, S669-S673 (1998)
	A3	J.T. LI, W.D. SCHNEIDER, R. BERNDT; <i>Low-temperature manipulation of Ag atoms and clusters on a Ag (110) surface</i> ; Appl. Phys. A 66, S675-S678 (1998)
	A4	M.T. CUBERES, R.R. SCHLITTLER, J.K. GIMZEWSKI; <i>Supramolecular assembly of individual C₆₀ molecules on a monolayer of 4, 4'-dimethylbianthrone molecules</i> ; Appl. Phys. A 66, S745-S748 (1998)
	A5	T. SHIMIZU, J.T. KIM, H. TOKUMOTO; <i>Tungsten silicide formation on an STM tip during atom manipulation</i> ; Appl. Phys. A 66, S771-S775 (1998)
	A6	G. MEYER, L. BARTELS, S. ZÖPHEL, K.H. RIEDER; <i>Lateral manipulation of adatoms and native substrate atoms with the low-temperature scanning tunneling microscope</i> ; Appl. Phys. A 68, 125-129 (1999)
	A7	X. HU, P. VON BLANCKENHAGEN; <i>Nano-scale metal cluster deposition using STM</i> ; Appl. Phys. A 68, 137-143 (1999)
	A8	A.A.G. REQUICHA, S. MELTZER, R. RESCH, D. LEWIS, B.E. KOEL, M.E. THOMPSON; <i>Layered nanoassembly of three-dimensional structures</i> ; Laboratory for Molecular Robotics, University of Southern California
	A9	J.W. LYDING, G.C. ABEIN, T.C. SHEN, C. WANG, J.R. TUCKER; <i>Nanometer scale patterning and oxidation of silicon surfaces with an ultrahigh vacuum scanning tunneling microscope</i> ; J. Vac. Sci. Technol. B 12(6), Nov/Dec 1994, pp. 3735-3740
	A10	G.C. ABEIN, M.C. HERSAM, D.S. THOMPSON, S.T. HWANG, H. CHOI, J.S. MOORE, AND J.W. LYDING; <i>Approaches to nanofabrication on Si(100) surfaces: Selective area chemical vapor deposition of metals and selective chemisorption of organic molecules</i> ; J. Vac. Sci. Technol. B 16(6), Nov/Dec 1998, pp. 3874-3878
	A11	R. RESCH, C. BAUR, A. BUGACOV, B.E. KOEL, A. MADHUKAR, A.A.G. REQUICHA, P. WILL; <i>Building and manipulating three-dimensional and linked two-dimensional structures of nanoparticles using scanning force microscopy</i> ; Langmuir The ACS Journal of Surfaces and Colloids, November 10, 1998, Vol. 14, No. 23
	A12	J.S. FOSTER, J.E. FROMMER, P.C. ARNETT; <i>Molecular manipulation using a tunneling microscope</i> ; IBM Research Division, Almaden Research Center, San Jose, California; Nature Vol. 331, January 28, 1988, pp. 324-326
	A13	G. DUJARDIN, A. MAYNE, O. ROBERT, F. ROSE, C. JOACHIM, H. TANG; <i>Vertical manipulation of individual atoms by a direct STM tip-surface contact on Ge(111)</i> ; Physical Review Letters, Vol. 80, No. 14, April 6, 1998, pp. 3085-3088

Examiner Signature		Date Considered	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

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Examiner Name	Jack I. Berman
Attorney Docket Number	34003.55

SHEET	2	OF	2
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OTHER PRIOR ART

[illegible]

**Examiner
Signature**

Date
Considered

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